



observations it is necessary to examine possible preferred orientation in the sample by diffraction using an area detector.

*Chiolite:* The diffractograms of the synthetic samples showed some unexpected features, which we first believed were caused by impurities formed during the preparation at high temperature. We found later that one of the starting reagents that had been acquired as high-purity grade for the synthesis, was actually contaminated. The synthetic preparation of chiolite has since been repeated from pure reagents and the product gives diffraction maxima in the expected angular positions.

Data for the natural mineral were of good quality.